

Docket No.: W1878.0169/P169

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Tomoaki Aihara

Application No.: 09/832,666

Art Unit: 2829

Filed: April 11, 2001

Examiner: J. Nguyen

For: METHOD AND APPARATUS FOR

INSPECTING SEMICONDUCTOR

DEVICE

FIRST PRELIMINARY AMENDMENT

U.S. Patent and Trademark Office 2011 South Clark Place Customer Window, Mail Stop RCE Crystal Plaza Two, Lobby, Room 1B03 Arlington, VA 22202

Dear Sir:

INTRODUCTORY COMMENTS

Prior to examination on the merits, please amend the above-identified U.S. patent application as follows:

FEE CALCULATION

Any additional fee required has been calculated as follows:

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Ť	Claims Remaining After Amendment	Highest Number Previously Paid		er	Number Extra Claims Present	Rate		Additional Fee
Total	29		29	=		X		.00
Independent	4	-	4	_		X		.00
First presentatio	on of Multiple Dep	ende	nt Clai	im(s)	(if applicable)			
		_				TO	TAL	.00

^{*}not less than 20

No additional fee is required.

In the event a fee is required or if any additional fee during the prosecution of this application is not paid, the Patent Office is authorized to charge any underpayment or credit any overpayment to Deposit Account No. 50-2215.

CONTINGENT EXTENSION REQUEST

If this communication is filed after the shortened statutory time period had elapsed and no separate Petition is enclosed, the Commissioner of Patents and Trademarks is petitioned, under 37 CFR 1.136(a), to extend the time for filing a response to the outstanding Office Action by the number of months which will avoid abandonment under 37 CFR 1.135. The fee under 37 CFR 1.17 should be charged to our Deposit Account No. 50-2215.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks/Arguments begin on page 9 of this paper.

^{**} not less than 3